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Docket No.: 67162-017

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of

Masayuki IKETANI

Serial No.: 10/619,476

Filed: July 16, 2003

: Customer Number: 20277

: Confirmation Number: 7350

: Group Art Unit: 2818

: Allowed: February 10, 2004

: Examiner: T. Q. Phan

For: SEMICONDUCTOR INTEGRATED CIRCUIT DEVICE CAPABLE OF  
SHORTENING PERIOD REQUIRED FOR PERFORMING DATA RETENTION TEST

**AMENDMENT UNDER 37 CFR 1.312**

Mail Stop Issue Fee  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

Please amend the above-identified application as follows: